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ANOVO CO., LTD.

QA Test Report

QUARK 45 Series

(Product Reliability Test)

Report No : 00anovo456

Report Date : July 10, 2009

Issue Stamp

Manager of QA Department

Approval

Test Engineer

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QALab Reliability test

1. High temperature operation test 1-3

2. Low temperature operation test 5-8

QA Lab Reliability test

Test Date : July 3, 2009 ~ July 10, 2009

Test Site : Anovo QA Environment Lab

Performed By : Wenxu Ding

Purpose : High-temperature normal operation of whether the circumstances

Test Standard : Reference IEC60068-2-2 Testing procedures

Test Bb : Dry Heat Test

Test Condition :

1. Test Temperature : 70°C
2. Test Times : 48 hrs
3. Test Software : Running Hot CPU Pro tester V4.3 & Passmark burn-in V5.1

Test program in WinXP

4. Test Environment Curve :



QA Lab Reliability test

Test Equipment : Programmable Temperature & Humidity Chamber

ANOVO CO. , Ltd.

Model : Anovo Quark45

Date of Calibration : 07/10/2009

Sample Configuration & Quantity Under Test :

Using one pieces of MI-945S with the following options installed :

1. Case : IGO-300-945S
2. CPU : Intel 1.6G ATOM
3. Motherboard : MI-945S
4. Memory : 1G KST DDRII
5. HDD : 160G SATA Serial
6. Power Supply : DC12V ATX

Performance Criteria :

Electronic function check:

1.All system functions must be checked with appropriate testing programs and should pass the inspection.

2.Running WinXP for OS, the system should not have degradation in its performance.

Mechanical function check:

1. The connectors and components should work properly without any interference.

2. All screws should be tightened up appropriately.

QA Lab Reliability test

Test Result :

There is no damage in electronic and mechanical functions.

Degradation has not been found.

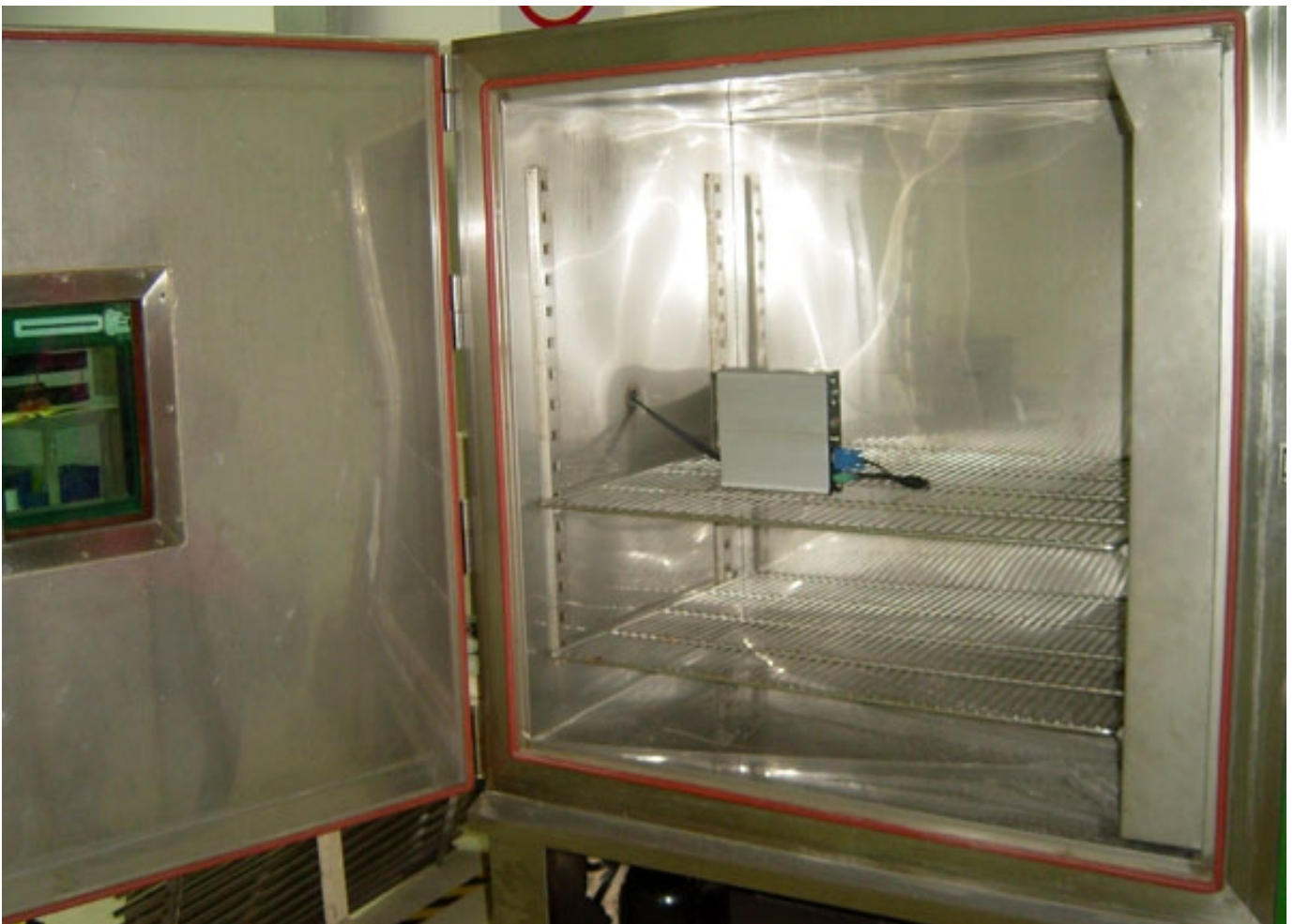
Performance is maintained with no incurable physical damage or

Degradation.

Conclusion :

Passed.

The Quark45 series meets high temperature operation test.

Photo :

Quark45 series high temperature operation test

QA Lab Reliability test

Test Date : July3 ~ 8, 2008

Test Site : Anovo QA Environment Lab

Performed By : Wenxu Ding

Purpose : Low-temperature normal operation of whether the circumstances

Test Standard : Reference IEC60068-2-1 Testing procedures

Test Ab : Cold Test

Test Condition :

Condition : (Test by 2 samples)

1. Test Temperature : -20°C
2. Test Times : 2 hrs
3. Test Software : Running Hot CPU Pro tester V4.3 & Passmark burn-in V5.1

test program in WinXP

4. Test Environment Curve :



QA Lab Reliability test

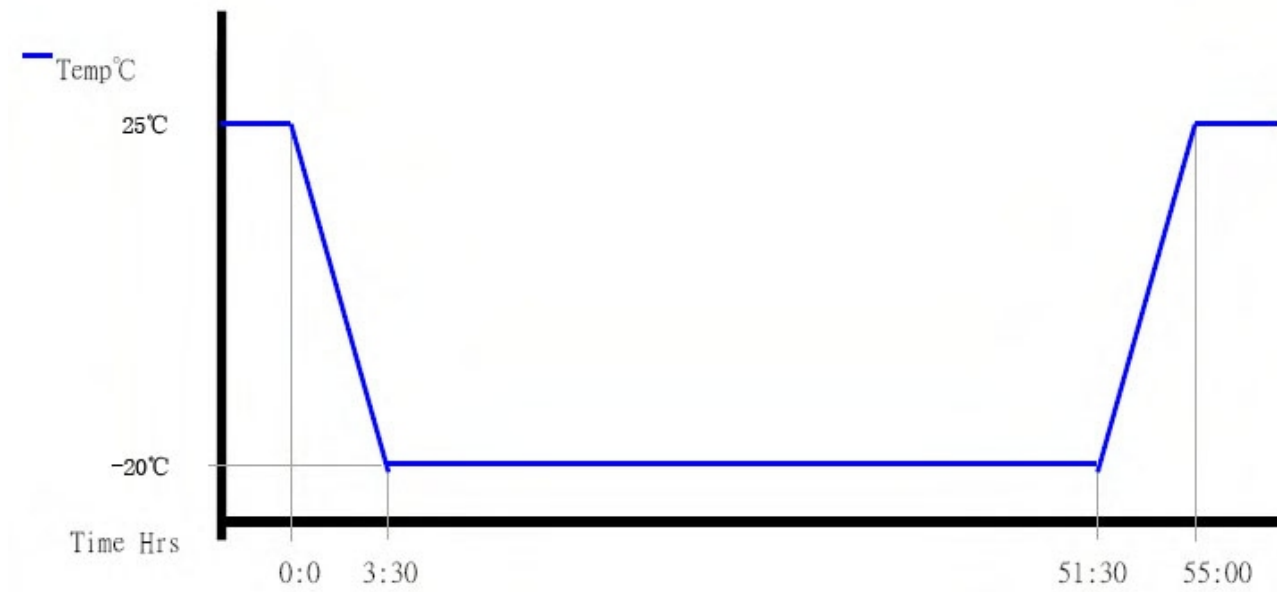
Condition II : (Test by 6 samples)

1. Test Temperature : -20°C

2. Test Times : 2 hrs

3. Test Software : Running Passmark burn-in V5.1 test program in WinXP

4. Test Environment Curve :



Test Equipment : Programmable Temperature & Humidity Chamber

Anovo Co. , LTD.

Model : ANOVO QUARK45

Date of Calibration : 07/08/2009

QA Lab Reliability test

Sample Configuration & Quantity Under Test :

Using one pieces of MIC-3392MIL with the following options installed :

1. Case : IGO-300-945S
2. CPU : Intel 1.6G ATOM
3. Motherboard : MI-945S
4. Memory : 1G KST DDRII
5. HDD : 160G SATA Serial
6. Power Supply : DC12V ATX

Performance Criteria :

Electronic function check:

- 1.All system functions must be checked with appropriate testing programs and should pass the inspection.
- 2.Running WinXP for OS, the system should not have degradation in its Performance.

QA Lab Reliability test

Mechanical function check:

1. The connectors and components should work properly without any interference.
2. All screws should be tightened up appropriately.

Test Result :

There is no damage in electronic and mechanical functions.

Degradation has not been found.

Performance is maintained with no incurable physical damage or degradation.

Conclusion :

Passed.

The Quark45 series meets low temperature operation test.

QA Lab Reliability test

Photo :

